

66376-279-7

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)	PATENT	#3
Herbert Thanner et al.)	Group Art Unit: Unknown	
Serial No.: To be assigned)	Examiner: Unknown	
Filed: March 4, 2002)		
PIEZOELECTRIC SINGLE CRYSTAL)		
ELEMENT)		



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INFORMATION DISCLOSURE STATEMENT

Washington, D.C.
March 4, 2002

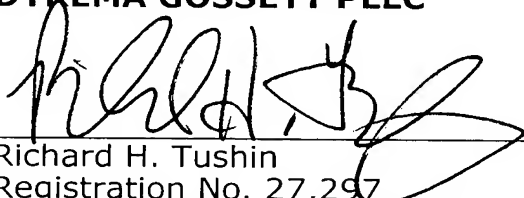
Honorable Director for Patents
Washington, D.C. 20231

Sir:

The applicants herewith submit copies of the documents discussed
on page 3 of this application.

Respectfully submitted,

DYKEMA GOSSETT PLLC


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(March 4, 2002)

Sheet 1 of 1

Form PTO-1449 U.S. Dept. of Commerce (Rev. 8-83) PATENT & TRADEMARK OFFICE		ATTY. DOCKET NO. 66376-279-7		SERIAL NO.	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT Herbert Thanner et al.			
		FILING DATE March 4, 2002		GROUP	

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
	A.W. Warner, "Design and Performance of Ultraprecise 2.5-mc Quartz Crystal Units," Bell Sys. Techn. J., Sept. 1960, pp. 1193-1217.
	Ch. Longet et al., "An Electrodeless BT Cut, 5 th Overtone Quartz Crystal Resonator at 50 MHZ," EFTF, 1995, pp. 141-145.
	R. C. Smythe et al., "Langasite, Langanite, and Langatate Resonators: Recent Results," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 816-820.
	<u>IEEE Standard on Piezoelectricity</u> , The Institute of Electrical and Electronics Engineers, New York, N.Y. (Jan. 29, 1988).
	<u>International Tables for X-Ray Crystallography</u> , The Kynoch Press, Birmingham, England (1969), pg. 255.
	B. V. Mill et al., "Synthesis, Growth and Some Properties of Single Crystals with the Ca ₃ Ga ₂ Ge ₄ O ₁₄ Structure," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 829-834.

EXAMINER	DATE CONSIDERED
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	